

MOS FIELD EFFECT TRANSISTOR μ PA1721

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The μ PA1721 is N-Channel MOS Field Effect Transistor designed for DC/DC converters and power management applications of notebook computers.

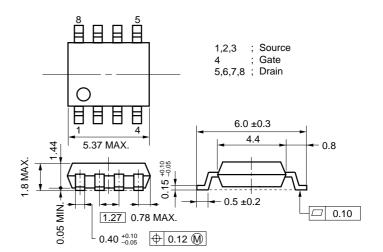
FEATURES

- · Low on-resistance
 - $R_{\text{DS(on)1}}$ = 10.5 $m\Omega$ MAX. (Vgs = 10 V, Ip = 5.0 A)
 - $R_{DS(on)2}$ = 14.0 $m\Omega$ MAX. (Vgs = 4.5 V, Ip = 5.0 A)
 - $R_{DS(on)3} = 17.0 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.0 \text{ V, ID} = 5.0 \text{ A)}$
- Low Ciss: Ciss = 2200 pF TYP.
- Built-in G-S protection diode
- Small and surface mount package (Power SOP8)

ORDERING INFORMATION

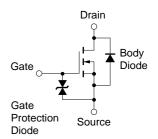
PART NUMBER	PACKAGE
μPA1721G	Power SOP8

PACKAGE DRAWING (Unit: mm)



ABSOLUTE MAXIMUM RATINGS (TA = 25°C, All terminals are connected.) EQUIVALENT CIRCUIT

Drain to Source Voltage (Vgs = 0 V)	VDSS	30	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V
Drain Current (DC)	ID(DC)	±10	Α
Drain Current (pulse) Note1	ID(pulse)	±40	Α
Total Power Dissipation $(T_A = 25^{\circ}C)^{Note2}$	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C



- **Notes 1.** PW \leq 10 μ s, Duty Cycle \leq 1 %
 - 2. Mounted on ceramic substrate of 1200 mm² x 2.2 mm

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

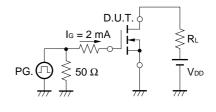
ELECTRICAL CHARACTERISTICS (TA = 25 °C, All terminals are connected.)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 5.0 A		8.0	10.5	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 5.0 A		10.0	14.0	mΩ
	RDS(on)3	Vgs = 4.0 V, ID = 5.0 A		12.0	17.0	mΩ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 5.0 A	7.0	14.0		S
Drain Leakage Current	Ipss	Vps = 30 V, Vgs = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	V _{DS} = 10 V		2200		pF
Output Capacitance	Coss	V _G S = 0 V		710		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		270		pF
Turn-on Delay Time	td(on)	ID = 5.0 A		30		ns
Rise Time	tr	V _{GS(on)} = 10 V		90		ns
Turn-off Delay Time	t _{d(off)}	V _{DD} = 15 V		90		ns
Fall Time	tf	$R_G = 10 \Omega$		50		ns
Total Gate Charge	QG	ID = 10 A		39		nC
Gate to Source Charge	Qgs	V _{DD} = 24 V		6.3		nC
Gate to Drain Charge	Q _{GD}	V _G S = 10 V		10.0		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 10 A, VGS = 0 V		0.8		V
Reverse Recovery Time	trr	IF = 10 A, VGS = 0 V		40		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ μs		50		nC

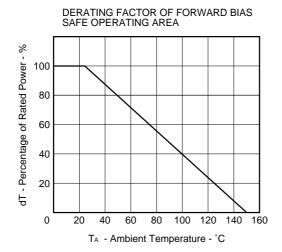
TEST CIRCUIT 1 SWITCHING TIME

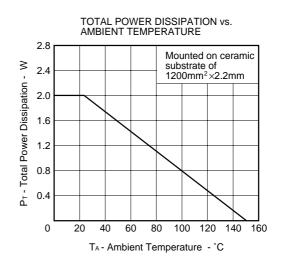
PG. $\bigcap_{RG} RG = 10 \Omega$ $V_{GS} \bigvee_{Wave Form} V_{GS} \bigvee_{Wave Form} V_{GS(on)} \bigvee_{VGS(on)} 90 \%$ $V_{GS} \bigvee_{Wave Form} V_{GS(on)} \bigvee_{VGS(on)} V_{GS(on)} \bigvee_{VGS(o$

TEST CIRCUIT 2 GATE CHARGE

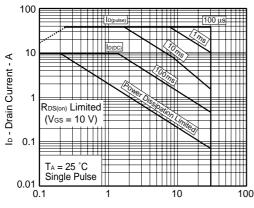


TYPICAL CHARACTERISTICS (TA = 25 °C)





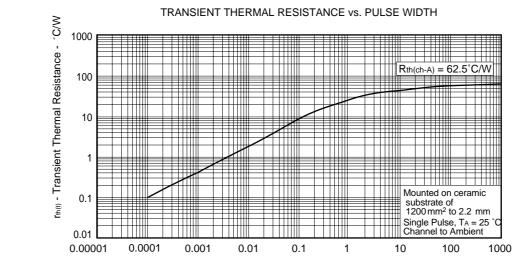
FORWARD BIAS SAFE OPERATING AREA



Note Mour

Mounted on ceramicsubstrate of 1200 mm² × 2.2 mm

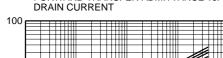
V_{DS} - Drain to Source Voltage - V



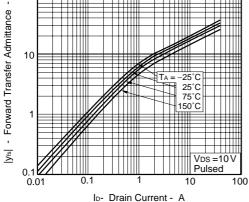
PW - Pulse Width - s

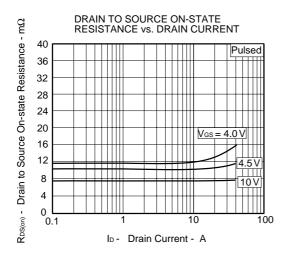
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FORWARD TRANSFER CHARACTERISTICS 100 Pulsed lo - Drain Current - $T_A = 150$ °C 10 75°C 25°C -25°C 1 0.1 0 3 V_{GS} - Gate to Source Voltage - V

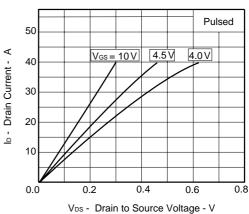


FORWARD TRANSFER ADMITTANCE vs.

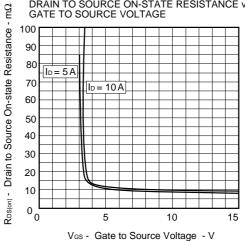




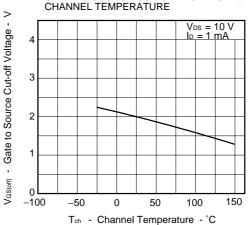
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE

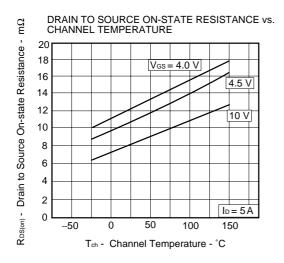


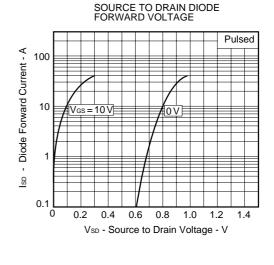
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

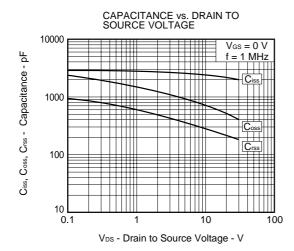


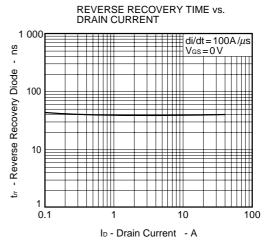
GATE TO SOURCE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE

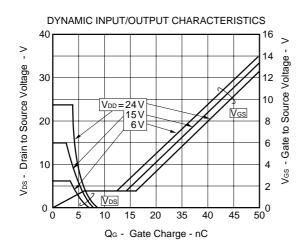












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NEC μ PA1721

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